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Erratum: Quality concerns caused by quality control — deformation of silicon strip detector modules in thermal cycling tests

Richard Salami ^{a,b,*} Luise Poley,^{a,b} Kirsten Affolder,^c Tony Affolder,^c Lukas Bayer,^d Ben Crick,^e Emily Duden,^{f,l} Ian George Dyckes,^g Vitaliy Fadeyev,^c Anne Fortman,^g Pavol Federič,^h Laura Franconi,^d Matthew Gignac,^c Shubham Gupta,^f John Hallford,^d Cole Helling,ⁱ Ewan Hill,^e Miao Hu,^g Jiří Kroll,^h Priyanka Kumari,^j Carlos Lacasta,^k Madison Levagood,ⁱ Hanlez Lopez,^k Len Morelos-Zaragoza,^c Meny Raviv Moshe,^l Aaron Petersen,^f Vicente Platero,^k Archa Devi Rajagopalan,^{a,b} Lisa Sitnikova,^d Carles Solaz,^k Urmila Soldevila,^k Peter Speers,^{a,b} Gerrit Van Nieuwenhuizen^l and Alex Zeng Wang^c

^aDepartment of Physics, Simon Fraser University, University Dr W, Burnaby, Canada

^bTRIUMF, Wesbrook Mall, Vancouver, Canada

^cSanta Cruz Institute of Particle Physics, University of California, High Street, Santa Cruz, U.S.A.

^dDeutsches Elektronen-Synchrotron, Notkestraße, Hamburg, Germany

^eDepartment of Physics, University of Toronto, Saint George St., Toronto, Canada

^fMartin A. Fisher School of Physics, Brandeis University, Waltham, U.S.A.

^gLawrence Berkeley National Laboratory, Cyclotron Road, Berkeley, U.S.A.

^hInstitute of Particle and Nuclear Physics, Charles University, Ke Karlovu, Prague, Czech Republic

ⁱUniversity of British Columbia, Department of Physics, Agricultural Road, Vancouver, Canada

^jDepartment of Physics and Astronomy, York University, Keele Street, Toronto, Canada

^kInstituto de Física Corpuscular, CSIC-Universidad de Valencia, c/ Catedrático José Beltrán, Paterna, Spain

^lBrookhaven National Laboratory, Rochester Street, Upton, U.S.A.

E-mail: ros3@sfu.ca, ros3@sfu.ca

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*Corresponding author.



Due to a typesetting oversight, a correction is missing from the original paper:

- Table 1: the correct entry for thickness of the silicon sensor is “305-335 μm ”. See the correct table below.

Table 1. Module component dimensions for endcap and barrel variants [3].

Component	Material	Thickness
Sensor	Silicon	305-335 μm
Hybrids (Endcap)	Copper, Polyimide	240-285 μm
Hybrids (Barrel)	Copper, Polyimide	378-462 μm
Powerboard (Endcap)	Copper, Polyimide	218-322 μm
Powerboard (Barrel)	Copper, Polyimide	385 μm

References

- [1] ...
- [2] ...
- [3] ITK STRIP MODULES group, *QC: Metrology procedures — modules*, presented at the *Czech ATLAS ITk Strip group status report*, Prague, Czech Republic, November 21 (2021).